

**Search Notes**

Application/Control No.

10/510,254

Examiner

Hieu P. Nguyen

Applicant(s)/Patent under  
Reexamination

DEKKERS ET AL.

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
330	258	1/4/2006	HN
330	295	1/3/2006	HN
330	252	1/3/2006	HN
330	253	1/4/2006	HN
330	84	1/4/2006	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
MOTTOLA STEVEN J	1/4/2006	HN